Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/679,170	DACHE ET AL.
Examiner	**Art Unit**
Kin-Chan Chen	1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	6/7/05	K-CC
	710		
	712		
	723		
	725		
	745		
	756		
	757		
	106		
438	107	6/7/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keywords search USPAT, USPGT-PUB, EPO, JPO, Derwent IBM-TDB	6/7/05	K-CC
inventor search	6/7/05	K-CC